

1-Mbit (128 K × 8) Static RAM

Features

- Pin- and function-compatible with CY7C1019CV33
- High speed

 □ t_{AA} = 10 ns
- Low Active Power
 □ I_{CC} = 60 mA @ 10 ns
- Low CMOS Standby Power
 □ I_{SB2} = 3 mA
- 2.0 V Data retention
- Automatic power-down when deselected
- CMOS for optimum speed/power
- Center power/ground pinout
- Easy memory expansion with $\overline{\text{CE}}$ and $\overline{\text{OE}}$ options
- Available in Pb-free 32-pin 400-Mil wide Molded SOJ, 32-pin TSOP II and 48-ball VFBGA packages

Functional Description

The CY7C1019DV33 is a high-performance CMOS static RAM organized as 131,072 words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable (CE), an active LOW Output Enable (OE), and three-state drivers. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

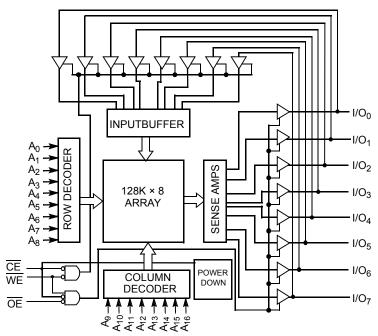
Writing to the device is accomplished by taking Chip Enable (\overline{CE}) and Write Enable (\overline{WE}) inputs LOW. Data on the eight I/O pins $(I/O_0$ through $I/O_7)$ is then written into the location specified on the address pins $(A_0$ through A_{16}).

Reading from the device is accomplished by taking Chip Enable (CE) and Output Enable (OE) LOW while forcing Write Enable (WE) HIGH. Under these conditions, the contents of the memory location specified by the address pins will appear on the I/O pins.

The eight input/output pins (I/O₀ through I/O₇) are <u>placed</u> in a high-impedance state when the device is deselected (CE HIGH), the outputs are <u>disabled</u> (\overline{OE} HIGH), or during a write operation (\overline{CE} LOW, and \overline{WE} LOW).

The CY7C1019DV33 is available in Pb-free 32-pin 400-Mil wide Molded SOJ, 32-pin TSOP II and 48-ball VFBGA packages.

Logic Block Diagram



CY7C1019DV33



Contents

Selection Guide	
Pin Configurations	3
Maximum Ratings	4
Operating Range	4
Electrical Characteristics	4
Capacitance	5
Thermal Resistance	5
AC Test Loads and Waveforms	5
Switching Characteristics	
Data Retention Characteristics	
Data Retention Waveform	
Switching Waveforms	
Truth Table	

Ordering Information	11
Ordering Code Definitions	11
Package Diagrams	12
Acronyms	14
Document Conventions	14
Units of Measure	14
Document History Page	15
Sales, Solutions, and Legal Information	
Worldwide Sales and Design Support	
Products	16
PSoC Solutions	16



Selection Guide

	-10 (Industrial)	Unit
Maximum Access Time	10	ns
Maximum Operating Current	60	mA
Maximum Standby Current	3	mA

Pin Configurations

Figure 1. 48-ball VFBGA (6 × 8 × 1 mm) (Top View) [1]

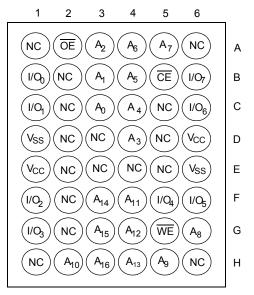
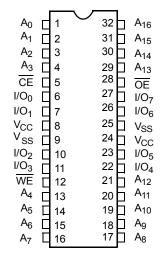


Figure 2. 32-pin SOJ / TSOP II (Top View)



Note

^{1.} NC pins are not connected on the die.



Maximum Ratings

DC Input Voltage [2]	0.3 V to V _{CC} + 0.3 V
Current into Outputs (LOW)	20 mA
Static Discharge Voltage (per MIL-STD-883, Method 3015)	> 2001 V
Latch-up Current	> 200 mA

Operating Range

Rar	ige	Ambient Temperature	V _{CC}	Speed
Indus	strial	–40 °C to +85 °C	$3.3 \text{ V} \pm 0.3 \text{ V}$	10 ns

Electrical Characteristics

Over the Operating Range

Doromotor	Description	Toot Conditions		-10 (Industrial)		Unit
Parameter	Description	rest Conditions	Test Conditions		Max	
V _{OH}	Output HIGH voltage	Min V_{CC} , $I_{OH} = -4.0 \text{ mA}$		2.4	-	V
V_{OL}	Output LOW voltage	Min V_{CC} , I_{OL} = 8.0 mA		-	0.4	V
V _{IH}	Input HIGH voltage			2.0	V _{CC} + 0.3	V
V _{IL}	Input LOW voltage [2]			-0.3	0.8	V
I _{IX}	Input leakage current	$GND \leq V_{IN} \leq V_{CC}$		– 1	+1	μА
I _{OZ}	Output leakage current	$GND \le V_{IN} \le V_{CC}$, output disabled		– 1	+1	μΑ
I _{CC}	V _{CC} operating supply current	V _{CC} = Max, I _{OUT} = 0 mA,	100 MHz	_	60	mA
		$f = f_{MAX} = 1/t_{RC}$	83 MHz	_	55	mA
			66 MHz	_	45	mA
			40 MHz	-	30	mA
I _{SB1}	Automatic CE power-down current – TTL inputs	$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{IH}}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{or} \text{V}_{\text{IN}} \leq \text{V}_{\text{IL}}, \text{f} = \text{f}_{\text{MAX}} \end{aligned}$		_	10	mA
I _{SB2}	Automatic CE power-down current – CMOS inputs	$\begin{aligned} &\text{Max V}_{\text{CC}}, \ \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V or V}_{\text{IN}} \leq 0.3 \text{ V}, \text{f} = \end{aligned}$	0	-	3	mA

Note

Document Number: 38-05481 Rev. *F

^{2.} $V_{IL(min)}$ = -2.0 V and $V_{IH(max)}$ = V_{CC} + 1 V for pulse durations of less than 5 ns.



Capacitance

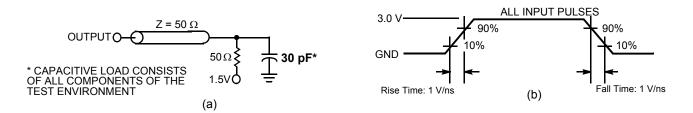
Parameter [3]	Description	Test Conditions	Max	Unit
C _{IN}	Input Capacitance	$T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz}, V_{CC} = 3.3 \text{V}$	8	pF
C _{OUT}	Output Capacitance		8	pF

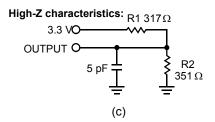
Thermal Resistance

Parameter [3]	Description	Test Conditions	32-pin SOJ	32-pin TSOP II	48-ball VFBGA	Unit
Θ_{JA}	(Junction to Ambient)	Still Air, soldered on a 3 × 4.5 inch, four-layer printed circuit		62.22	36	°C/W
$\Theta_{\sf JC}$	Thermal Resistance (Junction to Case)	board	38.14	21.43	9	°C/W

AC Test Loads and Waveforms

Figure 3. AC Test Loads and Waveforms [4]





- Tested initially and after any design or process changes that may affect these parameters.
 AC characteristics (except High Z) are tested using the load conditions shown in Figure 3 (a). High Z characteristics are tested for all speeds using the test load shown in Figure 3 (c).

Document Number: 38-05481 Rev. *F Page 5 of 16



Switching Characteristics

Over the Operating Range

Parameter [5]	Post total	-10 (Inc	-10 (Industrial)	
Parameter [9]	Description	Min	Max	Unit
Read Cycle		•	•	
t _{power} ^[6]	V _{CC} (typical) to the first access	100	_	μS
t _{RC}	Read cycle time	10	_	ns
t _{AA}	Address to data valid	_	10	ns
t _{OHA}	Data hold from address change	3	_	ns
t _{ACE}	CE LOW to data valid	_	10	ns
t _{DOE}	OE LOW to data valid	_	5	ns
t _{LZOE}	OE LOW to low Z [7]	0	_	ns
t _{HZOE}	OE HIGH to high Z [7, 8]	_	5	ns
t _{LZCE}	CE LOW to low Z [7]	3	_	ns
t _{HZCE}	CE HIGH to high Z [7, 8]	_	5	ns
t _{PU} ^[9]	CE LOW to power-up	0	_	ns
t _{PD} ^[9]	CE HIGH to power-down	_	10	ns
Write Cycle [10	, 11]			
t _{WC}	Write cycle time	10	_	ns
t _{SCE}	CE LOW to write end	8	_	ns
t _{AW}	Address set-up to write end	8	_	ns
t _{HA}	Address hold from write end	0	_	ns
t _{SA}	Address set-up to write start	0	_	ns
t _{PWE}	WE pulse width	7	_	ns
t _{SD}	Data set-up to write end	5	_	ns
t _{HD}	Data hold from write end	0	_	ns
t _{LZWE}	WE HIGH to low Z [7]	3	_	ns
t _{HZWE}	WE LOW to high Z [7, 8]	_	5	ns

- 5. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.

- test conditions assume signal transition with or 3 his or less, tilling reference levels of 10 to 3.0 v.

 the power gives the minimum amount of time that the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and voltage condition, the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and values are the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and values are the power supply should be at typical V_{CC} values until the first memory access can be performed. At any given temperature and values are the p
- The internal write time of the memory is defined by the overlap of CE LOW and WE LOW. CE and WE must be LOW to initiate a write, and the transition of any of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.
 The minimum write cycle time for Write Cycle no. 3 (WE controlled, OE LOW) is the sum of t_{HZWE} and t_{SD}.



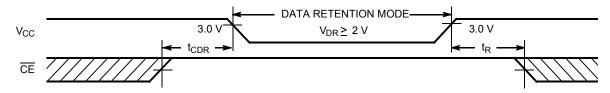
Data Retention Characteristics

Over the Operating Range

Parameter	Description	Conditions	Min	Max	Unit
V _{DR}	V _{CC} for data retention		2.0	-	V
I _{CCDR}	Data retention current	$V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V},$ $V_{IN} \ge V_{CC} - 0.3 \text{ V} \text{ or } V_{IN} \le 0.3 \text{ V}$	_	3	mA
t _{CDR} ^[12]	Chip deselect to data retention time		0	_	ns
t _R ^[13]	Operation recovery time		t _{RC}	_	ns

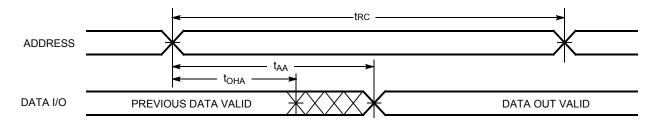
Data Retention Waveform

Figure 4. Data Retention Waveform



Switching Waveforms

Figure 5. Read Cycle No. 1 (Address Transition Controlled) [14, 15]



^{12.} Tested initially and after any design or process changes that may affect these parameters.

13. Full device operation requires linear V_{CC} ramp from V_{DR} to V_{CC(min.)} ≥ 50 μs or stable at V_{CC(min.)} ≥ 50 μs.

14. Device is continuously selected. OE, CE = V_{IL}.

^{15.} WE is HIGH for Read cycle.



Switching Waveforms (continued)

Figure 6. Read Cycle No. 2 (OE Controlled) [16, 17]

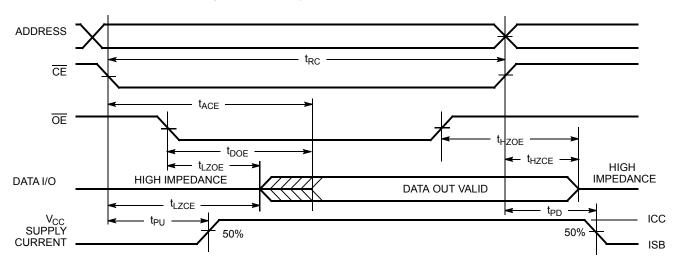
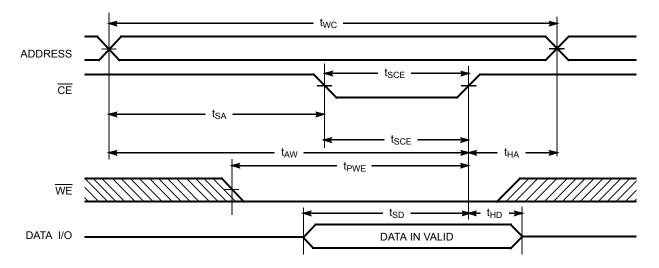


Figure 7. Write Cycle No. 1 (CE Controlled) [18, 19]



Notes

16. WE is HIGH for Read cycle.

17. Address valid prior to or coincident with $\overline{\text{CE}}$ transition LOW.

18. Data I/O is high impedance if $\overline{\text{OE}} = V_{\text{IH}}$.

19. If $\overline{\text{CE}}$ goes HIGH simultaneously with $\overline{\text{WE}}$ going HIGH, the output remains in a high-impedance state.



Switching Waveforms (continued)

Figure 8. Write Cycle No. 2 (WE Controlled, OE HIGH During Write) [20, 21]

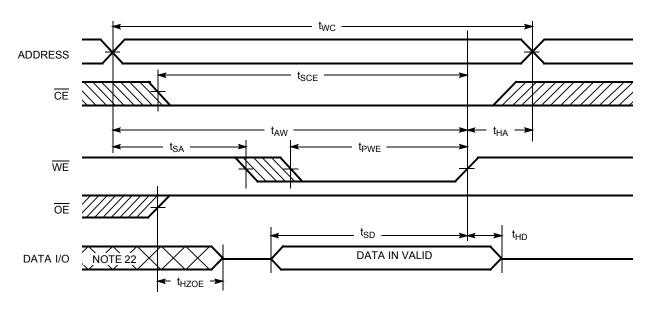
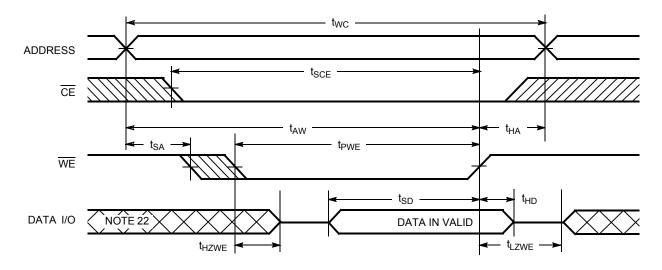


Figure 9. Write Cycle No. 3 ($\overline{\text{WE}}$ Controlled, $\overline{\text{OE}}$ LOW) [21, 23]



- 20. Data I/O is high impedance if $\overline{OE} = \underline{V_{IH}}$.
 21. If \overline{CE} goes HIGH simultaneously with \overline{WE} going HIGH, the output remains in a high-impedance state.
 22. During this period the I/Os are in the output state and input signals should not be applied.
 23. The minimum write cycle time for Write Cycle no. 3 (WE controlled, \overline{OE} LOW) is the sum of t_{HZWE} and t_{SD} .



Truth Table

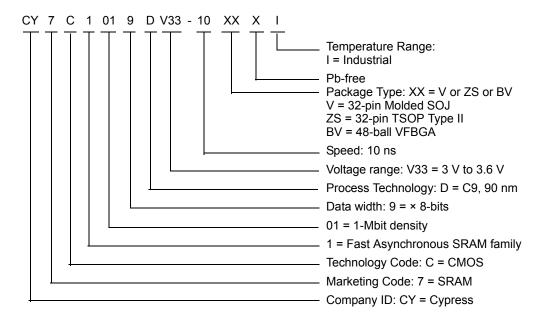
CE	OE	WE	I/O ₀ –I/O ₇	Mode	Power
Н	Х	Х	High Z	Power-Down	Standby (I _{SB})
L	L	Н	Data Out	Read	Active (I _{CC})
L	Х	L	Data In	Write	Active (I _{CC})
L	Н	Н	High Z	Selected, Outputs Disabled	Active (I _{CC})



Ordering Information

Speed (ns)	Ordering Code Packa Diagra		Package Type	Operating Range
10	CY7C1019DV33-10VXI	51-85033	32-pin (400-Mil) Molded SOJ (Pb-free)	Industrial
	CY7C1019DV33-10ZSXI	51-85095	32-pin TSOP Type II (Pb-free)	
	CY7C1019DV33-10BVXI	51-85150	48-ball VFBGA (Pb-free)	

Ordering Code Definitions



Please contact your local Cypress sales representative for availability of these parts.



Package Diagrams

Figure 10. 32-pin SOJ (400 Mils) V32.4 (Molded SOJ V33) Package Outline, 51-85033

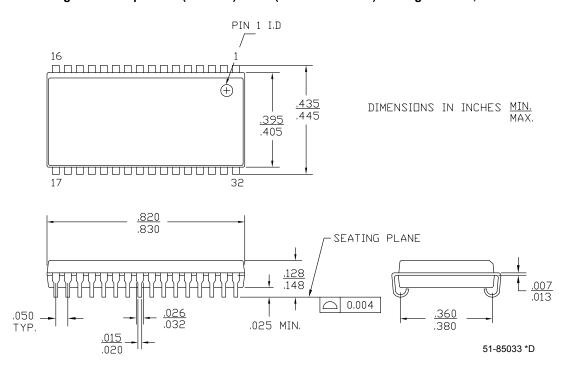
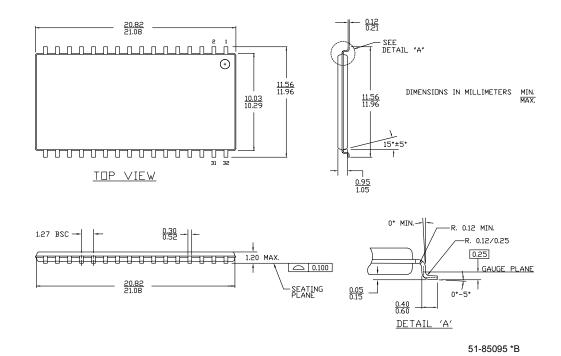


Figure 11. 32-pin TSOP II (20.95 × 11.76 × 1.0 mm) ZS32 Package Outline, 51-85095

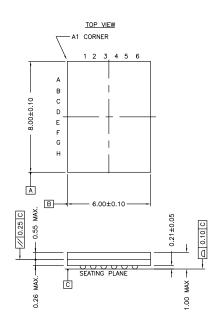


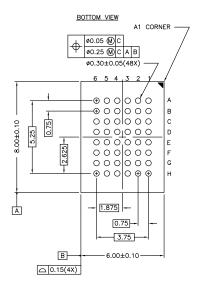
Document Number: 38-05481 Rev. *F Page 12 of 16



Package Diagrams (continued)

Figure 12. 48-ball VFBGA (6 × 8 × 1.0 mm) BV48/BZ48 Package Outline, 51-85150





51-85150 *G



Acronyms

Acronym	Description			
CE	chip enable			
CMOS	complementary metal oxide semiconductor			
I/O	input/output			
OE	output enable			
SOJ	small outline J-lead			
SRAM	static random access memory			
TSOP	thin small outline package			
TTL	transistor-transistor logic			
VFBGA	very fine-pitch ball gird array			
WE	write enable			

Document Conventions

Units of Measure

Symbol	Unit of Measure			
°C	degree Celsius			
MHz	megahertz			
μΑ	microampere			
μS	microsecond			
mA	milliampere			
mm	millimeter			
ns	nanosecond			
Ω	ohm			
%	percent			
pF	picofarad			
V	volt			
W	watt			



Document History Page

Rev.	ECN No.	Issue Date	Orig. of Change	Description of Change
**	201560	See ECN	SWI	Advance Information data sheet for C9 IPP
*A	233750	See ECN	RKF	DC parameters modified as per EROS (Spec # 01-02165 Rev *A) Pb-free Offering in Ordering Information
*B	262950	See ECN	RKF	Added Data Retention Characteristics table Added T _{power} Spec in Switching Characteristics table Shaded Ordering Information
*C	307598	See ECN	RKF	Reduced Speed bins to -8 and -10 ns
*D	520652	See ECN	VKN	Converted from Preliminary to Final Removed Commercial Operating range Removed 8 ns speed bin Added I _{CC} values for the frequencies 83 MHz, 66 MHz and 40 MHz Added 48-ball VFBGA package Updated Thermal Resistance table Updated Ordering Information table Changed Overshoot spec from V _{CC} + 2 V to V _{CC} + 1 V in footnote #3
*E	3110052	12/14/2010	AJU	Added Ordering Code Definitions. Updated Package Diagrams.
*F	3416342	10/20/2011	TAVA	Updated Functional Description (Removed the Note "For guidelines on SRAM system design, please refer to the 'System Design Guidelines' Cypress application note, available on the internet at www.cypress.com." and its reference in Functional Description). Updated Electrical Characteristics. Updated Switching Waveforms. Updated Package Diagrams. Added Acronyms and Units of Measure. Updated in new template.

Document Number: 38-05481 Rev. *F Page 15 of 16



Sales, Solutions, and Legal Information

Worldwide Sales and Design Support

Cypress maintains a worldwide network of offices, solution centers, manufacturer's representatives, and distributors. To find the office closest to you, visit us at cypress.com/sales.

Products

Automotive
Clocks & Buffers
Interface
Lighting & Power Control

Memory
Optical & Image Sensing
PSoC
Touch Sensing
USB Controllers
Wireless/RF

cypress.com/go/automotive cypress.com/go/clocks cypress.com/go/interface cypress.com/go/powerpsoc

cypress.com/go/plc cypress.com/go/memory cypress.com/go/image cypress.com/go/psoc cypress.com/go/touch cypress.com/go/USB cypress.com/go/wireless

PSoC Solutions

psoc.cypress.com/solutions PSoC 1 | PSoC 3 | PSoC 5

© Cypress Semiconductor Corporation, 2004-2011. The information contained herein is subject to change without notice. Cypress Semiconductor Corporation assumes no responsibility for the use of any circuitry other than circuitry embodied in a Cypress product. Nor does it convey or imply any license under patent or other rights. Cypress products are not warranted nor intended to be used for medical, life support, life saving, critical control or safety applications, unless pursuant to an express written agreement with Cypress. Furthermore, Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress products in life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Any Source Code (software and/or firmware) is owned by Cypress Semiconductor Corporation (Cypress) and is protected by and subject to worldwide patent protection (United States and foreign), United States copyright laws and international treaty provisions. Cypress hereby grants to licensee a personal, non-exclusive, non-transferable license to copy, use, modify, create derivative works of, and compile the Cypress Source Code and derivative works for the sole purpose of creating custom software and or firmware in support of licensee product to be used only in conjunction with a Cypress integrated circuit as specified in the applicable agreement. Any reproduction, modification, translation, compilation, or representation of this Source Code except as specified above is prohibited without the express written permission of Cypress.

Disclaimer: CYPRESS MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARD TO THIS MATERIAL, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE. Cypress reserves the right to make changes without further notice to the materials described herein. Cypress does not assume any liability arising out of the application or use of any product or circuit described herein. Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress' product in a life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Use may be limited by and subject to the applicable Cypress software license agreement.

Document Number: 38-05481 Rev. *F Revised October 20, 2011

Page 16 of 16

Mouser Electronics

Authorized Distributor

Click to View Pricing, Inventory, Delivery & Lifecycle Information:

Cypress Semiconductor:

CY7C1019DV33-10BVXIT CY7C1019DV33-10VXIT CY7C1019DV33-10ZSXIT